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Tel: +86-755-8981 8866 Fax: +86-755-8427 6832

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Address: A1208, Overseas Decoration Building, #122 Zhenhua RD., Futian, Shenzhen, China

30 A, 900 V very fast IGBT

Features

- Low on-losses
- Low on-voltage drop ($V_{CE(sat)}$)
- High current capability
- Low gate charge
- Ideal for soft switching application

Application

- Induction heating

Description

This IGBT utilizes the advanced PowerMESH™ process resulting in an excellent trade-off between switching performance and low on-state behavior.

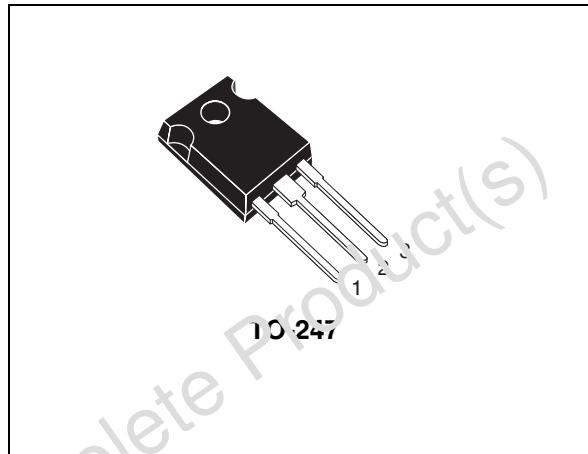


Figure 1. Internal schematic diagram

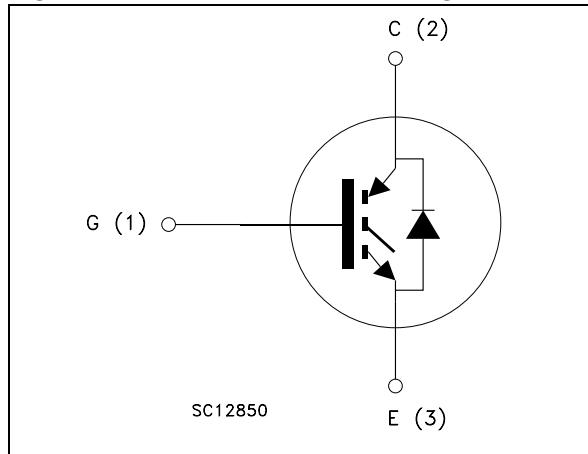


Table 1. Device summary

Order code	Marking	Package	Packaging
STGW30N90D	GW30N90D	TO-247	Tube

Contents

1	Electrical ratings	3
2	Electrical characteristics	4
2.1	Electrical characteristics (curves)	6
3	Test circuit	9
4	Package mechanical data	10
5	Revision history	12

1 Electrical ratings

Table 2. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{CES}	Collector-emitter voltage ($V_{GE} = 0$)	900	V
$I_C^{(1)}$	Collector current (continuous) at $T_C = 25^\circ\text{C}$	60	A
$I_C^{(1)}$	Collector current (continuous) at $T_C = 100^\circ\text{C}$	30	A
$I_{CL}^{(2)}$	Turn-off latching current	135	A
$I_{CP}^{(3)}$	Pulsed collector current	135	A
V_{GE}	Gate-emitter voltage	± 25	V
P_{TOT}	Total dissipation at $T_C = 25^\circ\text{C}$	220	W
I_F	Diode RMS forward current at $T_C = 25^\circ\text{C}$	30	A
I_{FSM}	Surge non repetitive forward current $t_p=10\text{ ms}$ sinusoidal	100	A
T_J	Operating junction temperature	-55 to 150	$^\circ\text{C}$

1. Calculated according to the iterative formula:

$$I_C(T_C) = \frac{T_{j(\max)} - T_C}{R_{thj-c} \times V_{CE(sat)(max)}(T_{j(\max)}, I_C(T_C))}$$

2. $V_{clamp}=900\text{V}$, $T_J=125^\circ\text{C}$, $R_{thj-c}=10\text{ }\Omega$, $V_{GE}=15\text{ V}$
 3. Pulse width limited by maximum junction temperature and turn-off within RBSOA

Table 3. Thermal data

Symbol	Parameter	Value	Unit
$R_{thj-case}$	Thermal resistance junction-case IGBT	0.57	$^\circ\text{C/W}$
	Thermal resistance junction-case (diode)	1.6	$^\circ\text{C/W}$
$R_{thj-amb}$	Thermal resistance junction-ambient	50	$^\circ\text{C/W}$

2 Electrical characteristics

($T_J = 25^\circ\text{C}$ unless otherwise specified)

Table 4. Static electrical characteristics

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(\text{BR})\text{CES}}$	Collector-emitter breakdown voltage ($V_{\text{GE}} = 0$)	$I_C = 1 \text{ mA}$	900			V
$V_{\text{CE}(\text{sat})}$	Collector-emitter saturation voltage	$V_{\text{GE}} = 15 \text{ V}, I_C = 20 \text{ A}$ $V_{\text{GE}} = 15 \text{ V}, I_C = 20 \text{ A}, T_J = 125^\circ\text{C}$		2.2 2.0	2.75	V V
$V_{\text{GE}(\text{th})}$	Gate threshold voltage	$V_{\text{CE}} = V_{\text{GE}}, I_C = 250 \mu\text{A}$	3.75		5.75	V
I_{CES}	Collector-emitter cut-off current ($V_{\text{GE}} = 0$)	$V_{\text{CE}} = 600 \text{ V}$ $V_{\text{CE}} = 600 \text{ V}, T_J = 125^\circ\text{C}$			500 10	μA mA
I_{GES}	Gate-emitter leakage current ($V_{\text{CE}} = 0$)	$V_{\text{GE}} = \pm 20 \text{ V}$			± 100	nA
$g_{\text{fs}}^{(1)}$	Forward transconductance	$V_{\text{CE}} = 25 \text{ V}, I_C = 20 \text{ A}$		14		S

1. Pulse duration: 300 μs , duty cycle 1.5%

Table 5. Dynamic

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
C_{ies}	Input capacitance			2510		pF
C_{oes}	Output capacitance		-	175	-	pF
C_{res}	Reverse transfer capacitance	$V_{\text{CE}} = 25 \text{ V}, f = 1 \text{ MHz}, V_{\text{GE}} = 0$	-	30		pF
Q_g	Total gate charge			110		nC
Q_{ge}	Gate-emitter charge	$V_{\text{CE}} = 900 \text{ V}, I_C = 20 \text{ A}, V_{\text{GE}} = 15 \text{ V}$	-	16	-	nC
Q_{gc}	Gate-collector charge			49		nC

Table 6. Switching on/off (inductive load)

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$ t_r (di/dt) _{on}	Turn-on delay time Current rise time Turn-on current slope	$V_{CC} = 900 \text{ V}$, $I_C = 20 \text{ A}$ $R_G = 10 \Omega$, $V_{GE} = 15 \text{ V}$, (see Figure 17)	-	29 11 1820	-	ns ns A/ μs
$t_{d(on)}$ t_r (di/dt) _{on}	Turn-on delay time Current rise time Turn-on current slope	$V_{CC} = 900 \text{ V}$, $I_C = 20 \text{ A}$ $R_G = 10 \Omega$, $V_{GE} = 15 \text{ V}$, $T_J = 125^\circ\text{C}$ (see Figure 17)	-	27 14 1580	-	ns ns A/ μs
$t_r(V_{off})$ $t_d(off)$ t_f	Off voltage rise time Turn-off delay time Current fall time	$V_{CC} = 900 \text{ V}$, $I_C = 20 \text{ A}$ $R_G = 10 \Omega$, $V_{GE} = 15 \text{ V}$, (see Figure 17)	-	90 275 312	-	ns ns ns
$t_r(V_{off})$ $t_d(off)$ t_f	Off voltage rise time Turn-off delay time Current fall time	$V_{CC} = 900 \text{ V}$, $I_C = 20 \text{ A}$ $R_G = 10 \Omega$, $V_{GE} = 15 \text{ V}$, $T_J = 125^\circ\text{C}$ (see Figure 17)	-	150 336 592	-	ns ns ns

Table 7. Switching energy (inductive load)

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$E_{on}^{(1)}$ $E_{off}^{(2)}$ E_{ts}	Turn-on switching losses Turn-off switching losses Total switching losses	$V_{CC} = 900 \text{ V}$, $I_C = 20 \text{ A}$ $R_G = 10 \Omega$, $V_{GE} = 15 \text{ V}$, (see Figure 17)	-	1660 4438 6098	-	μJ μJ μJ
$E_{on}^{(1)}$ $E_{off}^{(2)}$ E_{ts}	Turn-on switching losses Turn-off switching losses Total switching losses	$V_{CC} = 900 \text{ V}$, $I_C = 20 \text{ A}$ $R_G = 10 \Omega$, $V_{GE} = 15 \text{ V}$, $T_J = 125^\circ\text{C}$ (see Figure 17)	-	3015 6900 9915	-	μJ μJ μJ

1. E_{on} is the turn on losses when a typical diode is used in the test circuit in figure 2. If the IGBT is offered in a package with a co-pack diode, the co-pack diode is used as external diode. IGBTs & Diode are at the same temperature (25°C and 125°C)
2. Turn-off losses include also the tail of the collector current

Table 8. Collector-emitter diode

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
V_F	Forward on-voltage	$I_F = 20 \text{ A}$ $I_F = 20 \text{ A}$, $T_J = 125^\circ\text{C}$	-	1.9 1.7	2.5	V V
t_{rr} Q_{rr} I_{rrm}	Reverse recovery time Reverse recovery charge Reverse recovery current	$I_F = 20 \text{ A}$, $V_R = 27 \text{ V}$, $T_J = 125^\circ\text{C}$, $di/dt = 100 \text{ A}/\mu\text{s}$ (see Figure 20)	-	152 722 9	-	ns nC A

2.1 Electrical characteristics (curves)

Figure 2. Output characteristics

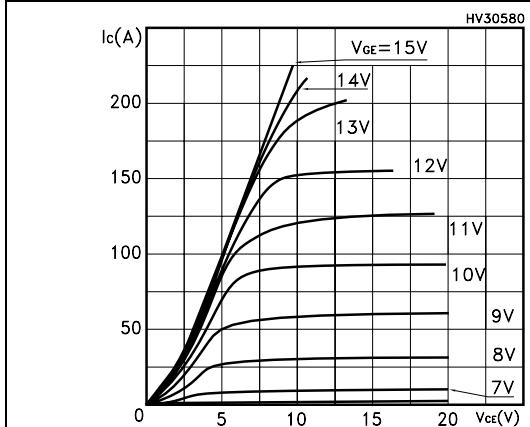


Figure 3. Transfer characteristics

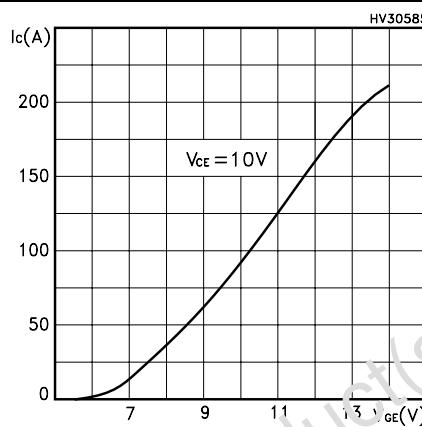


Figure 4. Transconductance

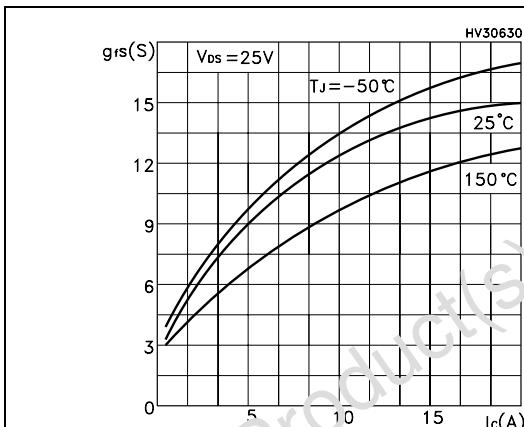


Figure 5. Collector-emitter on voltage vs. temperature

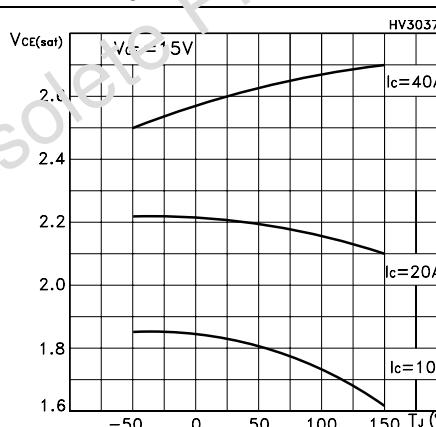


Figure 6. Gate charge vs. gate-source voltage

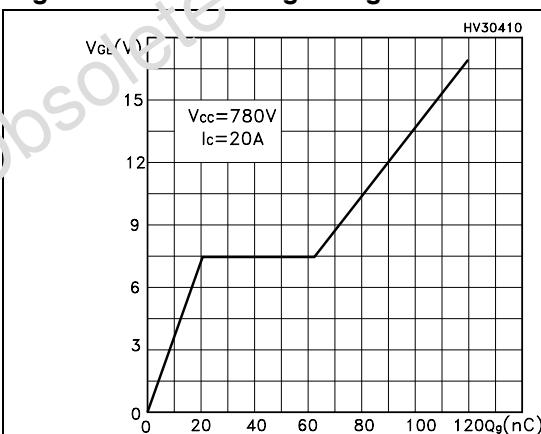


Figure 7. Capacitance variations

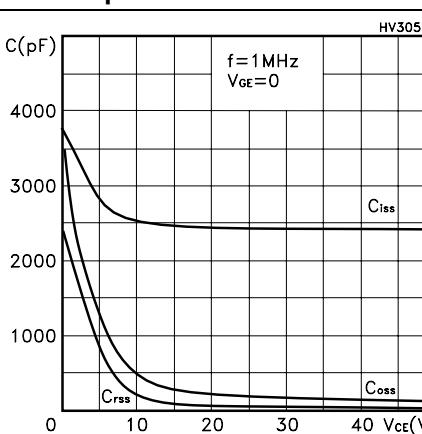


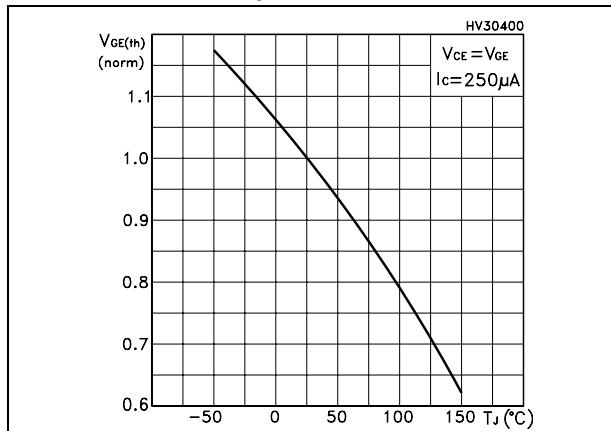
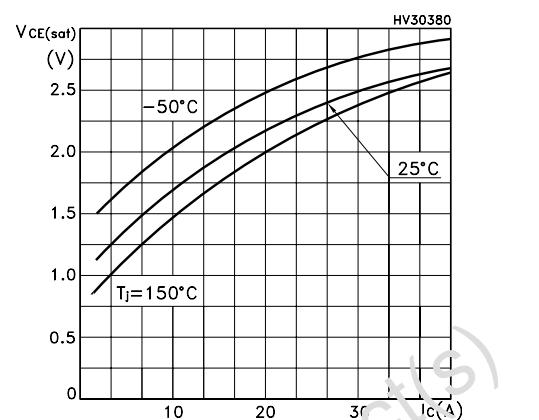
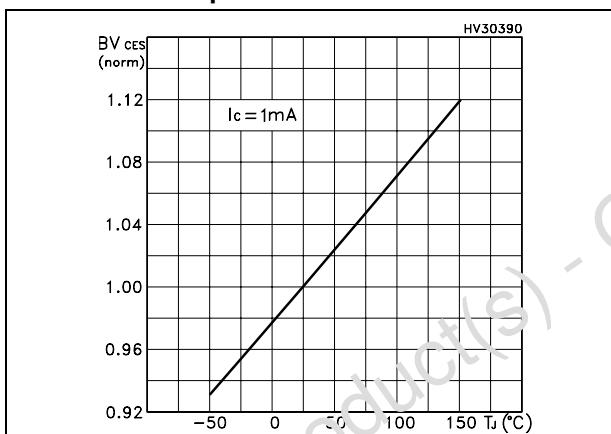
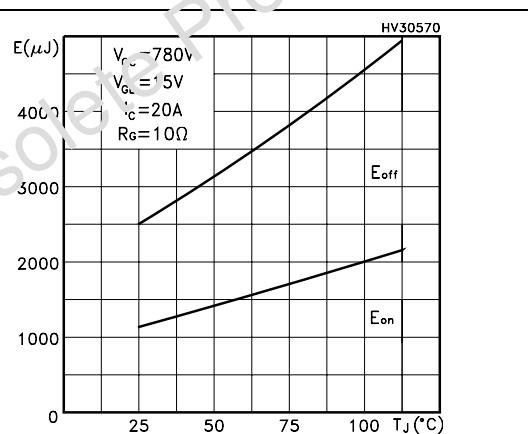
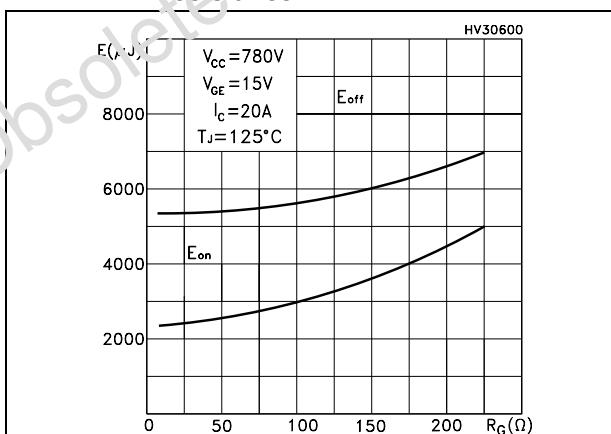
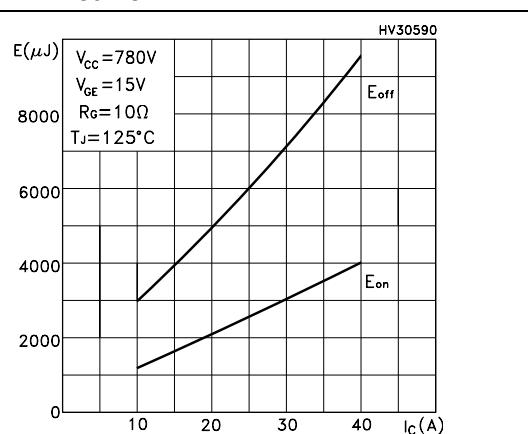
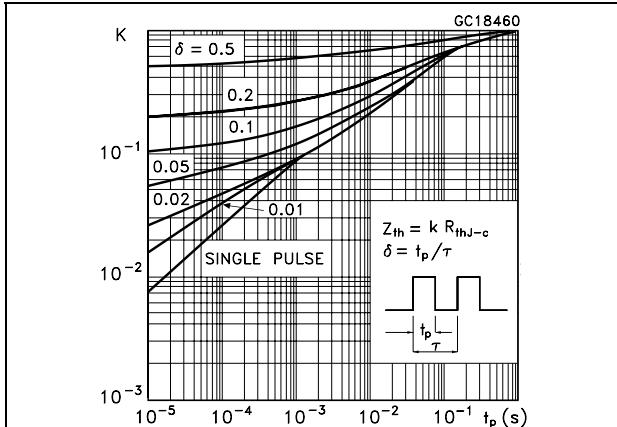
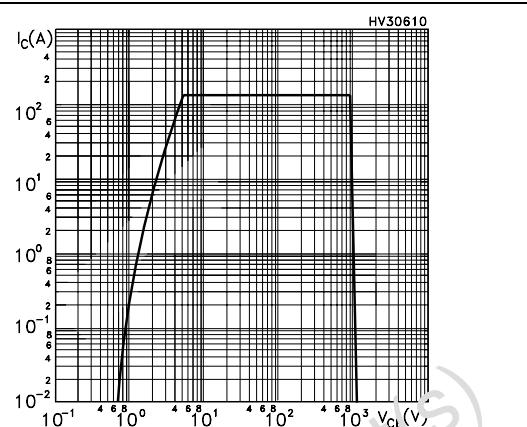
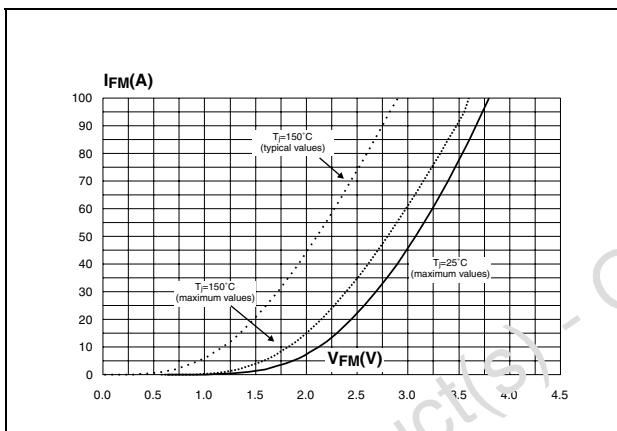
Figure 8. Normalized gate threshold voltage vs. temperature**Figure 9. Collector-emitter on voltage vs. collector current****Figure 10. Normalized breakdown voltage vs. temperature****Figure 11. Switching losses vs. temperature****Figure 12. Switching losses vs. gate resistance****Figure 13. Switching losses vs. collector current**

Figure 14. Thermal Impedance**Figure 15. Reverse biased SOA****Figure 16. Forward voltage drop vs. forward current**

3 Test circuit

Figure 17. Test circuit for inductive load switching

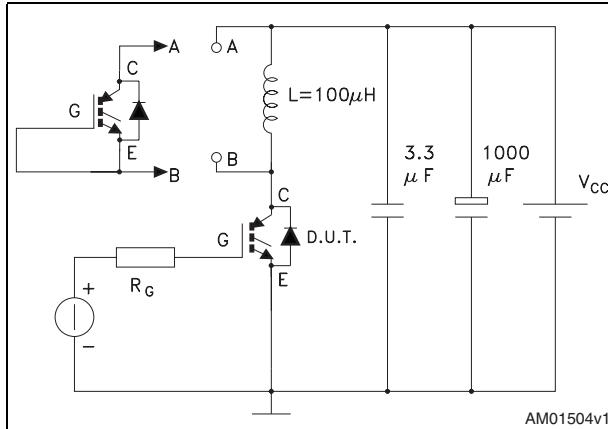


Figure 18. Gate charge test circuit

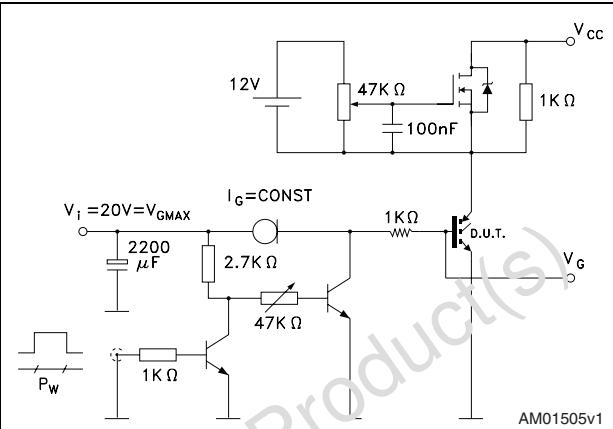


Figure 19. Switching waveform

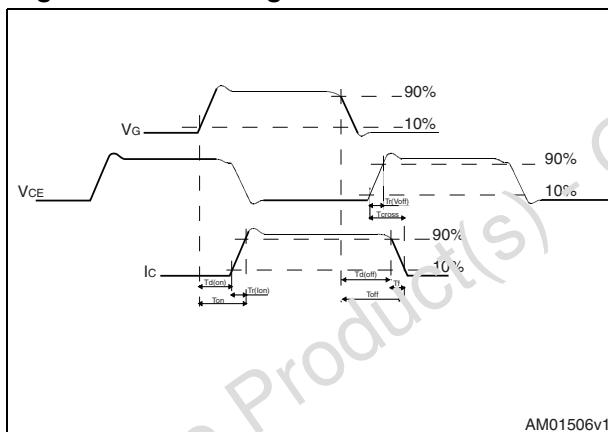
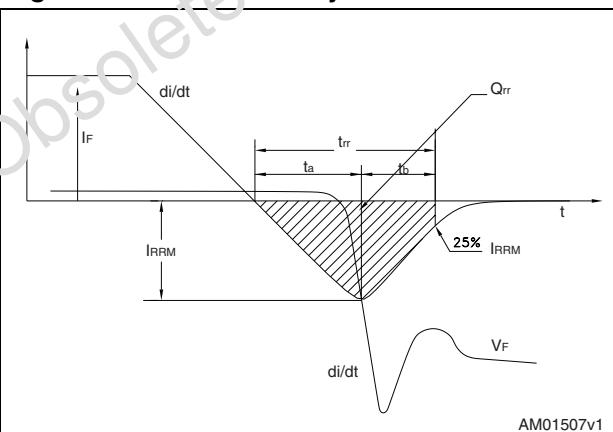


Figure 20. Diode recovery time waveform

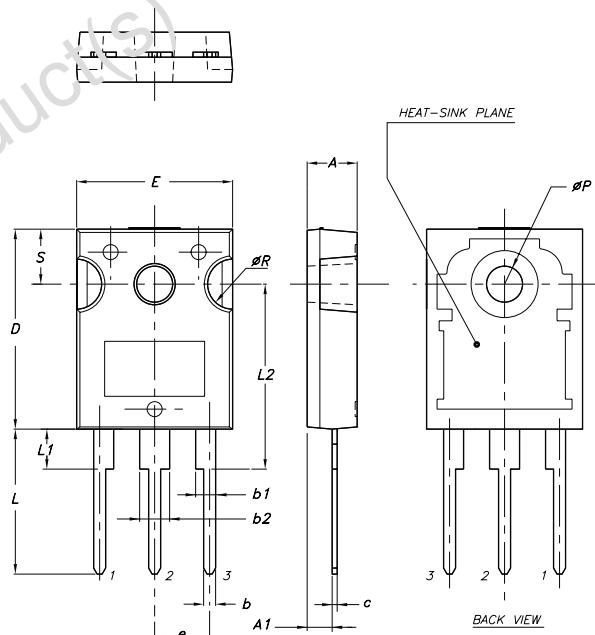


4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com. ECOPACK is an ST trademark.

TO-247 mechanical data

Dim.	mm.		
	Min.	Typ.	Max.
A	4.85		5.15
A1	2.20		2.60
b	1.0		1.40
b1	2.0		2.40
b2	3.0		3.40
c	0.40		0.80
D	19.85		20.15
E	15.45		15.75
e		5.45	
L	14.20		14.80
L1	3.70		4.30
L2		16.50	
ϕP	3.55		3.65
ϕR	4.50		5.50
S		5.50	



0075325_F

5 Revision history

Table 9. Document revision history

Date	Revision	Changes
19-Jul-2006	1	First issue.
02-Sep-2009	2	<ul style="list-style-type: none">- Document status promoted from preliminary data to datasheet- <i>Section 4: Package mechanical data</i> has been updated

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